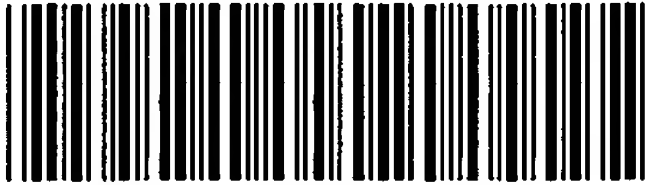


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/624,524	LEE ET AL.	
	Examiner	Art Unit	
	Nhan T. Tran	2622	

SEARCHED			
Class	Subclass	Date	Examiner
348	376	11/1/2006	NT
348	333.06	11/5/2006	NT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB) text search - see search history printout	11/1/2006	NT
348/14.01-14.02 (text search - see search history printout)	11/1/2006	NT
455/556.1, 556.2, 575.3 (text search - see search history printout)	11/1/2006	NT
348/373-376 (text search - see search history printout)	11/2/2006	NT
Talked to Aung Moe in class 455.	11/2/2005	NT
Inventorship search - see search history printout	11/6/2006	NT